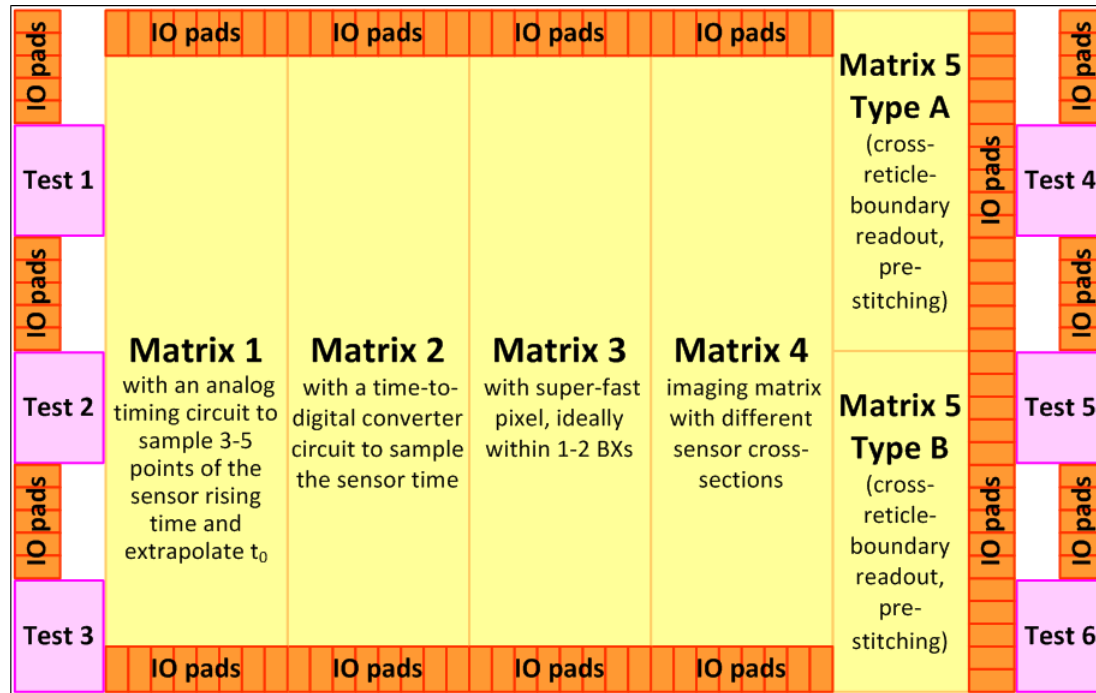


HV-CMOS submission within RD50 collaboration



Design effort:

- IFAE
- R. Casanova
- Uni. Barcelona
- O. Alonso
- Uni. Liverpool
- S. Powell
- E. Vilella
- C. Zhang

Scope for further design contributions...

- Test structure 1** Simple CMOS capacitors to study oxide thickness
- Test structure 2** 10 x 10 matrix of very small pixels with passive readout
- Test structure 3** 10 x 10 matrix of very small pixels with 3T-like readout
- Test structure 4** Small matrix of pixels for TCT, e-TCT and TPA-TCT measurements
- Test structure 5** Single pixels for sensor capacitance measurements
- Test structure 6** ...